

PATNO IS 5919561

DATE: SEPTEMBER 20, 2002
LIBRARY: PATENT
FILE: ALL

Your search request is:
PATNO IS 5919561

Number of PATENTS found with your search request through:
LEVEL 1... 1

Your search request has found 1 PATENT through Level 1.
To DISPLAY this PATENT press either the KWIC, FULL, CITE or SEGMENTS key.
To MODIFY your search request, press the M key (for MODFY) and then the ENTER key.

For further explanation, press the H key (for HELP) and then the ENTER key.

LEVEL 1 ~ 1 PATENT

1. 5919561 , July 6, 1999 , Reflector with resistant surface , Fuchs, Roman,
Schaffhausen, CHX; Schottner, Gerhard, Heilsbronn, DEX; Sandrock, Johannes
Martin, Hochberg, DEX, 08902964 (), Alusuisse Technology & Management, Ltd., CHX

CORE TERMS: layer, aluminium, reflector, functional, deposited, electrolyte,
anodising, reflective, coating, oxide ...

UNITED STATES PATENT AND TRADEMARK OFFICE GRANTED PATENT

5919561

<=1> GET 1st DRAWING SHEET OF 1

July 6, 1999

Reflector with resistant surface

REISSUE: July 5, 2001 - Reissue Application filed Jul. 5, 2001 (O.G. Mar. 5, 2002) Ex. Gp.: 1773; Re. S.N. 09/898,167 March 5, 2002

APPL-NO: 08902964 ()

FILED-DATE: July 30, 1997

GRANTED-DATE: July 6, 1999

CORE TERMS: layer, aluminium, reflector, functional, deposited, electrolyte, anodising, reflective, coating, oxide ...

ENGLISH-ABST:

Reflectors, for example, for lamps used for technical lighting purposes, having a surface which is resistant to mechanical and chemical attack and has high total reflectivity. The body (10) of the reflector, which is, for example, a rolled aluminum product such as a foil, a strip of a sheet, has a surface layer in the form of a layer system containing (a) a pretreatment layer (11), onto which is deposited (b) a functional layer (12) with silanes, having organo-functional groups, of a metal compound, and onto which is deposited (c) a metal-containing reflective layer (13). Layer (a) is deposited on the reflector body and increases the strength of bonding to the above lying layers (a) and (b). Layer (b) effects a flattening and increase in the mechanical strength of the above lying layer (c). The pretreatment layer can be a layer produced by anodic oxidation. The functional layer (b) can be a sol-gel layer. The reflective layer (c) can be a metallic reflective layer, in some cases with one or more protective layers, which are deposited, e.g., by vacuum thin layer deposition process.

5919561 OR 5,919,561

Your search request has found no ITEMS.

To edit the above request, use the arrow keys. Be sure to move the cursor to the end of the request before you enter it.

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5919561 OR 5,919,561

Your search request has found no CASES.

To edit the above request, use the arrow keys. Be sure to move the cursor to the end of the request before you enter it.

To enter a new search request, type it and press the ENTER key.

What you enter will be Search Level 1.

For further explanation, press the H key (for HELP) and then the ENTER key.

Questel Orbit QWEB

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QUESTEL.ORBIT (TM) 1998
Last connection: 20/09/02 15*28*50

20/09/02 15*34*53

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- EPAPAT contains all unique EPTEXT data. EPTEXT file removed
- New Patent Citation Commands: easy & precise - INFO PATCITE
- USAPPS Reloaded: Pricing, see INFO USAPPS
- USPCL: US Patent Class Definition Look-up File - INFO USPCL

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Query/Command : N

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Query/Command : FILE PLUSPAT

QUESTEL - Time in minutes : 1,10
The cost estimation below is based on Questel's
standard price list

Estimated cost :	0.95	USD
Cost estimated for the last database search :	0.95	USD
Estimated total session cost :	0.95	USD

Selected file: PLUSPAT

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Comprehensive Worldwide Patents database
New Patent Citation Commands & FAM Citation Report - see INFO PATCITE
Last update of file: 2002/09/20 (YYYY/MM/DD) 2002-37/UP (basic update)

Search statement 1

Query/Command : US5919561/PN

**** SS 1: Results 1**

Search statement 2

Query/Command : prt full nonstop legalall

<i>I / I PLUSPAT - ©QUESTEL-ORBIT - image</i>	
PN	- US5919561 A 19990706 [US5919561]
TI	(A) Reflector with resistant surface
PA	(A) ALUSUISSE LONZA SERVICES AG (CH)
IN	(A) FUCHS ROMAN (CH); SCHOTTNER GERHARD (DE); SANDROCK JOHANNES MARTIN (DE)
AP	US90296497 19970730 [1997US-0902964]
PR	CH200196 19960815 [1996CH-0002001] CH216596 19960903 [1996CH-0002165]
IC	(A) B32B-015/08
EC	C25D-011/18 G02B-001/10C
PCL	ORIGINAL (O) : 428336000; CROSS-REFERENCE (X) : 428215000 428216000 428450000 428912200
DT	Corresponding document
CT	US3274078; US4457587; US5356492; EP0358011; EP0495755; EP0568943; EP0610831; FR1247882; GB890465
STG	(A) United States patent
AB	Reflectors, for example, for lamps used for technical lighting purposes, having a surface which is resistant to mechanical and chemical attack and has high total reflectivity. The body (10) of the reflector, which is, for example, a rolled aluminum product such as a foil, a strip or a sheet, has a surface layer in the form of a layer system containing (a) a pretreatment layer (11), onto which is deposited (b) a functional layer (12) with lanes, having organo-functional groups, of a metal compound, and onto which is deposited (c) a metal-containing reflective layer (13). Layer (a) is deposited on the reflector body and increases the strength of bonding to the above lying layers (a) and (b). Layer (b) effects a flattening and increase in the mechanical strength of the above lying layer (c). The pretreatment layer can be a layer produced by anodic oxidation. The functional layer (b) can be a sol-gel layer. The reflective layer (c) can be a metallic reflective layer, in some cases with one or more protective layers, which are deposited, e.g., by vacuum thin layer deposition process.
<i>I / I LGST - ©LEGSTAT</i>	

Questel Orbit QWEB

PN	-	US 5919561 [US5919561]
AP	-	US 902964/97 19970730 [1997US-0902964]
DT	-	US-P
ACT	-	19970730 US/AE-A APPLICATION DATA (PATENT) US 902964/97 19970730 [1997US-0902964] 19970730 US/AS02 ASSIGNMENT OF ASSIGNOR'S INTEREST ALUSUISSE TECHNOLOGY & MANAGEMENT LTD. CH-8212 NEUHAUSEN AM RHEINFALL, SWITZERLAND * FUCHS, ROMAN : 19970721; SCHOTTNER, GERHARD : 19970721; SANDROCK, JOHANNES MARTIN : 19970721 19990706 US/A PATENT 20020305 US/RF REISSUE APPLICATION FILED 20010705
UP	-	2002-10

1/1 CRXX - ©CLAIMS/RRX

PN	-	5,919,561 A 19990706 [US5919561]
PA	-	Alusuisse Technology & Management Ltd CH
ACT	-	20010705 REISSUE REQUESTED ISSUE DATE OF O.G.: 20020305 REISSUE REQUEST NUMBER: 09/898167 EXAMINATION GROUP RESPONSIBLE FOR REISSUEPROCESS : 1773
Reissue Patent Number:		

1/1 PAST - ©Thomson Derwent

AN	-	200210-001220
PN	-	5919561 A [US5919561]
OG	-	2002-03-05
ACT	-	REISSUE APPLICATION FILED

Query/Command : FILE INPADOC

PLUSPAT - Time in minutes : 0,36
 The cost estimation below is based on Questel's
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Questel·Orbit QWEB

Estimated cost :	0.79	USD
Records displayed and billed :	1	
Estimated cost :	1.10	USD
Cost estimated for the last database search :	1.89	USD
Estimated total session cost :	2.84	USD

LGST - Time in minutes : 0,09
The cost estimation below is based on Questel's standard price list

Estimated cost :	0.09	USD
Records displayed and billed :	1	
Estimated cost :	0.57	USD
Cost estimated for the last database search :	0.66	USD
Estimated total session cost :	3.50	USD

CRXX - Time in minutes : 0,07
The cost estimation below is based on Questel's standard price list

Estimated cost :	0.10	USD
Records displayed and billed :	1	
Estimated cost :	5.00	USD
Cost estimated for the last database search :	5.10	USD
Estimated total session cost :	8.60	USD

PAST - Time in minutes : 0,10
The cost estimation below is based on Questel's standard price list

Estimated cost :	0.19	USD
Records displayed and billed :	1	
Estimated cost :	5.61	USD
Cost estimated for the last database search :	5.80	USD
Estimated total session cost :	14.40	USD

LITA - Time in minutes : 0,01
The cost estimation below is based on Questel's standard price list

Estimated cost :	0.01	USD
Cost estimated for the last database search :	0.01	USD
Estimated total session cost :	14.41	USD

Selected file: INPADOC

You are now connected to INPADOC
Covers 1968/1973 thru weekly updates (2002-37)
For information on content, ..INFO INPD.

Search statement 1

Query/Command : FAM US5919561/PN

1 Patent Groups

**** SS 1: Results 14**

Search statement 2

Query/Command : FAMSTATE NONSTOP

1 / 14 INPADOC - ©INPADOC		
PN	-	AT 217366 E 20020515 [ATE217366]
TI	-	REFLEKTOR MIT RESISTENTER OBERFLAECHE
IN	-	FUCHS ROMAN [CH]; SCHOTTNER GERHARD [DE]; SANDROCK JOHANNES MARTIN [DE]
PA	-	ALCAN TECHNOLOGY & MAN AG [CH]
AP	-	AT 97810524/97-EP 19970723 [1997EP-0810524]
PR	-	CH 2001/96-A 19960815 [1996CH-0002001] CH 2165/96-A 19960903 [1996CH-0002165]
IC	-	C25D-011/18; G02B-001/10
1 / 2 LEGALI - ©LEGSTAT		
PN	-	AT 217366 [ATE217366]
DT	-	AT-R
ACTE	-	20020515 AT/REF-P CORRESPONDS TO EP-PATENT (EP 824154 20020508 [EP-824154])
UP	-	2002-23
2 / 2 LEGALI - ©LEGSTAT		
PN	-	EP 824154 [EP-824154]
AP	-	EP 97810524/97 19970723 [1997EP-0810524]
DT	-	EP-P
ACTE	-	19970723 EP/AE-A EP-APPLICATION EP 97810524/97 19970723 [1997EP-0810524] 19980218 EP/AK-A1 [+] DESIGNATED CONTRACTING STATES IN AN APPLICATION WITH SEARCH REPORT: AT BE CH DE DK ES FI FR GB GR IE IT LI NL SE 19980218 EP/A1 [+] PUBLICATION OF APPLICATION WITH SEARCH REPORT

19981014 EP/17P [+]
REQUEST FOR EXAMINATION FILED
980818

19981028 EP/AKX [+]
PAYMENT OF DESIGNATION FEES
AT BE CH DE DK ES FI FR GB GR IE IT LI LU MC NL PT SE

19981028 EP/RBV [+]
DESIGNATED CONTRACTING STATES (CORRECTION):
AT BE CH DE DK ES FI FR GB GR IE IT LI LU MC NL PT SE

20000510 EP/17Q [+]
FIRST EXAMINATION REPORT
20000324

20011114 EP/RAP1
APPLICANT REASSIGNMENT (CORRECTION)
ALCAN TECHNOLOGY & MANAGEMENT AG

20020101 EP/REG; GB/IF02 [+]
GB: EUROPEAN PATENT IN FORCE AS OF 2002-01-01
<GB>

20020102 EP/RBV [+]
DESIGNATED CONTRACTING STATES (CORRECTION):
AT BE CH DE DK ES FI FR GB GR IE IT LI NL SE

20020508 EP/AK-B1 [+]
DESIGNATED CONTRACTING STATES MENTIONED IN A PATENT
SPECIFICATION:
AT BE CH DE DK ES FI FR GB GR IE IT LI NL SE

20020508 EP/B1 [+]
PATENT SPECIFICATION

20020508 EP/REF-R [+]
IN AUSTRIA REGISTERED AS:
(AT 217366 20020515 [ATE217366])

20020515 EP/REG; CH/EP [+]
CH: ENTRY IN THE NATIONAL PHASE
<CH>

20020612 EP/REG; IE/FG4D
IE: EUROPEAN PATENTS GRANTED DESIGNATING IRELAND
German
<IE>

20020613 EP/REF-P
CORRESPONDS TO:
(DE 59707198 20020613 [DE59707198])

Questel·Orbit QWEB

		20020826 EP/REG; DK/T3 [+] DK: TRANSLATION OF EP PATENT <DK>
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UP	-	2002-36
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2 / 14 INPADOC - ©INPADOC		
---------------------------	--	--

PN	-	AU 32465/97 A1 19980219 [AU9732465]
TI	-	REFLECTOR WITH RESISTANT SURFACE
IN	-	FUCHS ROMAN; SCHOTTNER GERHARD; SANDROCK JOHANNES MARTIN
PA	-	ALUSUISSE LONZA SERVICES AG
AP	-	AU 32465/97-A 19970804 [1997AU-0032465]
PR	-	CH 2001/96-A 19960815 [1996CH-0002001] CH 2165/96-A 19960903 [1996CH-0002165]
IC	-	G02B-001/10; G02B-005/08; B32B-031/12; B32B-033/00

3 / 14 INPADOC - ©INPADOC		
---------------------------	--	--

PN	-	CA 2212833 AA 19980215 [CA2212833]
TI	-	REFLECTOR WITH RESISTANT SURFACE
LA	-	ENG
IN	-	SANDROCK JOHANNES MARTIN [DE]; FUCHS ROMAN [CH]; SCHOTTNER GERHARD [DE]
PA	-	ALUSUISSE LONZA SERVICES AG [CH]
AP	-	CA 2212833/97-A 19970813 [1997CA-2212833]
PR	-	CH 2001/96-A 19960815 [1996CH-0002001] CH 2165/96-A 19960903 [1996CH-0002165]
IC	-	G02B-005/12

4 / 14 INPADOC - ©INPADOC		
---------------------------	--	--

PN	-	CH 691064 A 20010412 [CH-691064]
TI	-	REFLEKTOR MIT RESISTENTER OBERFLAECHE .
LA	-	GER
IN	-	FUCHS ROMAN [CH]; SCHOTTNER GERHARD DIPL-CHEM [DE]; SANDROCK JOHANNES MARTIN
PA	-	ALUSUISSE TECH & MAN AG [CH]
AP	-	CH 2165/96-A 19960903 [1996CH-0002165]
PR	-	CH 2165/96-A 19960903 [1996CH-0002165]
IC	-	C23C-014/02; C23C-016/02; F21V-007/22; G02B-001/10

1 / 2 LEGALI - ©LEGSTAT

PN	-	CH 691064 [CH-691064]
AP	-	CH 2165/96 19960903 [1996CH-0002165]
DT	-	CH-P
ACTE	-	19960903 CH/AE-A APPLIED (PATENT APPLICATION) CH 2165/96 19960903 [1996CH-0002165]
UP	-	2001-17

2 / 2 LEGALI - ©LEGSTAT

AP	-	CH 2165/96 0 [1996CH-0002165]
DT	-	CH-A
ACTE	-	20010412 CH/AGA-A [+] PUBLISHED AS MAIN PATENT (CH 691064 20010412 [CH-691064])
UP	-	2001-17

5 / 14 INPADOC - ©INPADOC

PN	-	CH 691063 A 20010412 [CH-691063]
TI	-	REFLEKTOR MIT RESISTENTER OBERFLAECHE .
LA	-	GER
IN	-	FUCHS ROMAN [CH]; SCHOTTNER GERHARD DIPL-CHEM [DE]; SANDROCK JOHANNES MARTIN
PA	-	ALUSUISSE TECH & MAN AG [CH]
AP	-	CH 2001/96-A 19960815 [1996CH-0002001]
PR	-	CH 2001/96-A 19960815 [1996CH-0002001]
IC	-	C23C-014/02; C23C-016/02; F21V-007/22; G02B-001/10

1 / 2 LEGALI - ©LEGSTAT

PN	-	CH 691063 [CH-691063]
AP	-	CH 2001/96 19960815 [1996CH-0002001]
DT	-	CH-P
ACTE	-	19960815 CH/AE-A APPLIED (PATENT APPLICATION) CH 2001/96 19960815 [1996CH-0002001]

UP | - | 2001-17

2/2 LEGALI - ©LEGSTAT

AP | - | CH 2001/96 0 [1996CH-0002001]

DT | - | CH-A

ACTE | - | 20010412 CH/AGA-A [+]
PUBLISHED AS MAIN PATENT
(CH 691063 20010412 [CH-691063])

UP | - | 2001-17

6/14 INPADOC - ©INPADOC

PN | - | DE 59707198 C0 20020613 [DE59707198]

TI | - | REFLEKTOR MIT RESISTENTER OBERFLAECHE

IN | - | FUCHS ROMAN [CH]; SCHOTTNER GERHARD [DE]; SANDROCK
JOHANNES MARTIN [DE]

PA | - | ALCAN TECHNOLOGY & MAN AG NEUH [CH]

AP | - | DE 59707198/97-A 19970723 [1997DE-5007198]

PR | - | CH 2001/96-A 19960815 [1996CH-0002001]
CH 2165/96-A 19960903 [1996CH-0002165]

IC | - | C25D-011/18; G02B-001/10

1/2 LEGALI - ©LEGSTAT

PN | - | DE 59707198 [DE59707198]

DT | - | DE-P

ACTE | - | 20020613 DE/REF-P
CORRESPONDS TO
(EP 824154 20020613 [EP-824154])

UP | - | 2002-24

2/2 LEGALI - ©LEGSTAT

PN | - | EP 824154 [EP-824154]

AP | - | EP 97810524/97 19970723 [1997EP-0810524]

DT | - | EP-P

ACTE | - | 19970723 EP/AE-A
EP-APPLICATION
EP 97810524/97 19970723 [1997EP-0810524]

19980218 EP/AK-A1 [+]
DESIGNATED CONTRACTING STATES IN AN APPLICATION WITH
SEARCH REPORT:
AT BE CH DE DK ES FI FR GB GR IE IT LI NL SE

19980218 EP/A1 [+]
PUBLICATION OF APPLICATION WITH SEARCH REPORT

19981014 EP/17P [+]
REQUEST FOR EXAMINATION FILED
980818

19981028 EP/AKX [+]
PAYMENT OF DESIGNATION FEES
AT BE CH DE DK ES FI FR GB GR IE IT LI LU MC NL PT SE

19981028 EP/RBV [+]
DESIGNATED CONTRACTING STATES (CORRECTION):
AT BE CH DE DK ES FI FR GB GR IE IT LI LU MC NL PT SE

20000510 EP/17Q [+]
FIRST EXAMINATION REPORT
20000324

20011114 EP/RAP1
APPLICANT REASSIGNMENT (CORRECTION)
ALCAN TECHNOLOGY & MANAGEMENT AG

20020101 EP/REG; GB/IF02 [+]
GB: EUROPEAN PATENT IN FORCE AS OF 2002-01-01
<GB>

20020102 EP/RBV [+]
DESIGNATED CONTRACTING STATES (CORRECTION):
AT BE CH DE DK ES FI FR GB GR IE IT LI NL SE

20020508 EP/AK-B1 [+]
DESIGNATED CONTRACTING STATES MENTIONED IN A PATENT
SPECIFICATION:
AT BE CH DE DK ES FI FR GB GR IE IT LI NL SE

20020508 EP/B1 [+]
PATENT SPECIFICATION

20020508 EP/REF-R [+]
IN AUSTRIA REGISTERED AS:
(AT 217366 20020515 [ATE217366])

20020515 EP/REG; CH/EP [+]
CH: ENTRY IN THE NATIONAL PHASE
<CH>

20020612 EP/REG; IE/FG4D

IE: EUROPEAN PATENTS GRANTED DESIGNATING IRELAND

German
<IE>

20020613 EP/REF-P
CORRESPONDS TO:
(DE 59707198 20020613 [DE59707198])

20020826 EP/REG; DK/T3 [+]
DK: TRANSLATION OF EP PATENT
<DK>

UP	-	2002-36
----	---	---------

7 / 14 INPADOC - ©INPADOC

PN	-	DK 824154 T3 20020826 [DK-824154]
TI	-	REFLEKTOR MED RESISTENT OVERFLADE
IN	-	FUCHS ROMAN [CH]; SCHOTTNER GERHARD [DE]; SANDROCK JOHANNES MARTIN [DE]
PA	-	ALCAN TECHNOLOGY & MAN AG [CH]
AP	-	DK 97810524/97-A 19970723 [1997DK-0810524]
PR	-	CH 2001/96-A 19960815 [1996CH-0002001] CH 2165/96-A 19960903 [1996CH-0002165]
IC	-	C25D-011/18; G02B-001/10

8 / 14 INPADOC - ©INPADOC

PN	-	EP 824154 B1 20020508 [EP-824154]
TI	-	REFLECTOR WITH RESISTANT SURFACE
LA	-	GER
IN	-	FUCHS ROMAN [CH]; SCHOTTNER GERHARD [DE]; SANDROCK JOHANNES MARTIN [DE]
PA	-	ALCAN TECHNOLOGY & MAN AG [CH]
AP	-	EP 97810524/97-A 19970723 [1997EP-0810524]
PR	-	CH 2001/96-A 19960815 [1996CH-0002001] CH 2165/96-A 19960903 [1996CH-0002165]
IC	-	C25D-011/18; G02B-001/10
DS	-	AT* BE* CH* DE* DK* ES* FI* FR* GB* GR* IE* IT* LI* NL* SE*

1 / 3 LEGALI - ©LEGSTAT

PN	-	DE 59707198 [DE59707198]
----	---	--------------------------

DT	-	DE-P
ACTE	-	20020613 DE/REF-P CORRESPONDS TO (EP 824154 20020613 [EP-824154])
UP	-	2002-24
<hr/>		
<i>2 / 3 LEGALI - ©LEGSTAT</i>		
PN	-	AT 217366 [ATE217366]
DT	-	AT-R
ACTE	-	20020515 AT/REF-P CORRESPONDS TO EP-PATENT (EP 824154 20020508 [EP-824154])
UP	-	2002-23
<hr/>		
<i>3 / 3 LEGALI - ©LEGSTAT</i>		
PN	-	EP 824154 [EP-824154]
AP	-	EP 97810524/97 19970723 [1997EP-0810524]
DT	-	EP-P
ACTE	-	<p>19970723 EP/AE-A EP-APPLICATION EP 97810524/97 19970723 [1997EP-0810524]</p> <p>19980218 EP/AK-A1 [+] DESIGNATED CONTRACTING STATES IN AN APPLICATION WITH SEARCH REPORT: AT BE CH DE DK ES FI FR GB GR IE IT LI NL SE</p> <p>19980218 EP/A1 [+] PUBLICATION OF APPLICATION WITH SEARCH REPORT</p> <p>19981014 EP/17P [+] REQUEST FOR EXAMINATION FILED 980818</p> <p>19981028 EP/AKX [+] PAYMENT OF DESIGNATION FEES AT BE CH DE DK ES FI FR GB GR IE IT LI LU MC NL PT SE</p> <p>19981028 EP/RBV [+] DESIGNATED CONTRACTING STATES (CORRECTION): AT BE CH DE DK ES FI FR GB GR IE IT LI LU MC NL PT SE</p> <p>20000510 EP/17Q [+] FIRST EXAMINATION REPORT 20000324</p>

20011114 EP/RAP1
 APPLICANT REASSIGNMENT (CORRECTION)
 ALCAN TECHNOLOGY & MANAGEMENT AG

20020101 EP/REG; GB/IF02 [+]
 GB: EUROPEAN PATENT IN FORCE AS OF 2002-01-01
 <GB>

20020102 EP/RBV [+]
 DESIGNATED CONTRACTING STATES (CORRECTION):
 AT BE CH DE DK ES FI FR GB GR IE IT LI NL SE

20020508 EP/AK-B1 [+]
 DESIGNATED CONTRACTING STATES MENTIONED IN A PATENT
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 AT BE CH DE DK ES FI FR GB GR IE IT LI NL SE

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20020508 EP/REF-R [+]
 IN AUSTRIA REGISTERED AS:
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 <CH>

20020612 EP/REG; IE/FG4D
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 German
 <IE>

20020613 EP/REF-P
 CORRESPONDS TO:
 (DE 59707198 20020613 [DE59707198])

20020826 EP/REG; DK/T3 [+]
 DK: TRANSLATION OF EP PATENT
 <DK>

UP	-	2002-36
----	---	---------

9 / 14 INPADOC - ©INPADOC		
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PN	-	EP 824154 A1 19980218 [EP-824154]
----	---	-----------------------------------

TI	-	REFLECTOR WITH RESISTANT SURFACE
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LA	-	GER
----	---	-----

IN	-	FUCHS ROMAN [CH]; SCHOTTNER GERHARD [DE]; SANDROCK JOHANNES MARTIN [DE]
----	---	---

PA	-	ALUSUISSE LONZA SERVICES AG [CH]
AP	-	EP 97810524/97-A 19970723 [1997EP-0810524]
PR	-	CH 2001/96-A 19960815 [1996CH-0002001] CH 2165/96-A 19960903 [1996CH-0002165]
IC	-	C25D-011/18; G02B-001/10
DS	-	AT* BE* CH* DE* DK* ES* FI* FR* GB* GR* IE* IT* LI* NL* SE*

1 / 3 LEGALI - ©LEGSTAT

PN	-	DE 59707198 [DE59707198]
DT	-	DE-P
ACTE	-	20020613 DE/REF-P CORRESPONDS TO (EP 824154 20020613 [EP-824154])
UP	-	2002-24

2 / 3 LEGALI - ©LEGSTAT

PN	-	AT 217366 [ATE217366]
DT	-	AT-R
ACTE	-	20020515 AT/REF-P CORRESPONDS TO EP-PATENT (EP 824154 20020508 [EP-824154])
UP	-	2002-23

3 / 3 LEGALI - ©LEGSTAT

PN	-	EP 824154 [EP-824154]
AP	-	EP 97810524/97 19970723 [1997EP-0810524]
DT	-	EP-P
ACTE	-	19970723 EP/AE-A EP-APPLICATION EP 97810524/97 19970723 [1997EP-0810524] 19980218 EP/AK-A1 [+] DESIGNATED CONTRACTING STATES IN AN APPLICATION WITH SEARCH REPORT: AT BE CH DE DK ES FI FR GB GR IE IT LI NL SE 19980218 EP/A1 [+] PUBLICATION OF APPLICATION WITH SEARCH REPORT 19981014 EP/17P [+]

REQUEST FOR EXAMINATION FILED
980818

19981028 EP/AKX [+]
PAYMENT OF DESIGNATION FEES
AT BE CH DE DK ES FI FR GB GR IE IT LI LU MC NL PT SE

19981028 EP/RBV [+]
DESIGNATED CONTRACTING STATES (CORRECTION):
AT BE CH DE DK ES FI FR GB GR IE IT LI LU MC NL PT SE

20000510 EP/17Q [+]
FIRST EXAMINATION REPORT
20000324

20011114 EP/RAP1
APPLICANT REASSIGNMENT (CORRECTION)
ALCAN TECHNOLOGY & MANAGEMENT AG

20020101 EP/REG; GB/IF02 [+]
GB: EUROPEAN PATENT IN FORCE AS OF 2002-01-01
<GB>

20020102 EP/RBV [+]
DESIGNATED CONTRACTING STATES (CORRECTION):
AT BE CH DE DK ES FI FR GB GR IE IT LI NL SE

20020508 EP/AK-B1 [+]
DESIGNATED CONTRACTING STATES MENTIONED IN A PATENT
SPECIFICATION:
AT BE CH DE DK ES FI FR GB GR IE IT LI NL SE

20020508 EP/B1 [+]
PATENT SPECIFICATION

20020508 EP/REF-R [+]
IN AUSTRIA REGISTERED AS:
(AT 217366 20020515 [ATE217366])

20020515 EP/REG; CH/EP [+]
CH: ENTRY IN THE NATIONAL PHASE
<CH>

20020612 EP/REG; IE/FG4D
IE: EUROPEAN PATENTS GRANTED DESIGNATING IRELAND
German
<IE>

20020613 EP/REF-P
CORRESPONDS TO:
(DE 59707198 20020613 [DE59707198])

20020826 EP/REG; DK/T3 [+]

DK: TRANSLATION OF EP PATENT

<DK>

UP - 2002-36

10/14 INPADOC - ©INPADOC

PN	-	JP 10090505 A2 19980410 [JP10090505]
TI	-	REFLECTOR AND ITS PRODUCTION
IN	-	FUCHS ROMAN; SCHOTTNER GERHARD; SANDROCK JOHANNES MARTIN
PA	-	ALUSUISSE TECHNOL & MANAG LTD
AP	-	JP 217919/97-A 19970813 [1997JP-0217919]
PR	-	CH 2001/96-A 19960815 [1996CH-0002001] CH 2165/96-A 19960903 [1996CH-0002165]
IC	-	G02B-005/08; B32B-015/04; C09D-183/04

11/14 INPADOC - ©INPADOC

PN	-	NO 973736 A0 19970813 [NO9703736]
TI	-	REFLEKTOR MED RESISTENT OVERFLATE, SAMT FREMSTILLING OG ANVENDELSE DERAV
IN	-	FUCHS ROMAN [CH]; SCHOTTNER GERHARD [DE]; SANDROCK JOHANNES MARTIN [DE]
PA	-	ALUSUISSE LONZA SERVICES AG [CH]
AP	-	NO 973736/97-A 19970813 [1997NO-0003736]
PR	-	CH 2001/96-A 19960815 [1996CH-0002001] CH 2165/96-A 19960903 [1996CH-0002165]
IC	-	C23C-000/00

12/14 INPADOC - ©INPADOC

PN	-	NO 973736 A 19980216 [NO9703736]
TI	-	REFLEKTOR MED RESISTENT OVERFLATE, SAMT FREMSTILLING OG ANVENDELSE DERAV
IN	-	FUCHS ROMAN [CH]; SCHOTTNER GERHARD [DE]; SANDROCK JOHANNES MARTIN [DE]
PA	-	ALUSUISSE LONZA SERVICES AG [CH]
AP	-	NO 973736/97-A 19970813 [1997NO-0003736]
PR	-	CH 2001/96-A 19960815 [1996CH-0002001] CH 2165/96-A 19960903 [1996CH-0002165]
IC	-	C23C-028/00; C23C-014/22; C23C-016/00; C23C-026/00; C25D-011/00; C25D-011/04

13 / 14 INPADOC - ©INPADOC

PN	-	TW 467968 B 20011211 [TW-467968]
TI	-	REFLECTOR WITH RESISTANT SURFACE
IN	-	FUCHS ROMAN [DE]; SCHOTTNER GERHARD [DE]; SANDROCK JOHANNES MARTIN [DE]
PA	-	ALUSUISSE LONZA SERVICES AG [CH]
AP	-	TW 86111640/97-A 19970814 [1997TW-0111640]
PR	-	CH 2165/96-A 19960903 [1996CH-0002165] CH 2001/96-A 19960815 [1996CH-0002001]
IC	-	C23C-028/00; G02B-017/06

14 / 14 INPADOC - ©INPADOC

PN	-	US 5919561 A 19990706 [US5919561]
TI	-	REFLECTOR WITH RESISTANT SURFACE
IN	-	FUCHS ROMAN [CH]; SCHOTTNER GERHARD [DE]; SANDROCK JOHANNES MARTIN [DE]
PA	-	ALUSUISSE LONZA SERVICES AG [CH]
AP	-	US 902964/97-A 19970730 [1997US-0902964]
PR	-	CH 2001/96-A 19960815 [1996CH-0002001] CH 2165/96-A 19960903 [1996CH-0002165]
IC	-	B32B-015/08

1 / 1 LEGALI - ©LEGSTAT

PN	-	US 5919561 [US5919561]
AP	-	US 902964/97 19970730 [1997US-0902964]
DT	-	US-P
ACTE	-	19970730 US/AE-A APPLICATION DATA (PATENT) US 902964/97 19970730 [1997US-0902964] 19970730 US/AS02 ASSIGNMENT OF ASSIGNOR'S INTEREST ALUSUISSE TECHNOLOGY & MANAGEMENT LTD. CH-8212 NEUHAUSEN AM RHEINFALL, SWITZERLAND * FUCHS, ROMAN : 19970721; SCHOTTNER, GERHARD : 19970721; SANDROCK, JOHANNES MARTIN : 19970721 19990706 US/A PATENT 20020305 US/RF

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